

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Deok-Yong KIM

Serial No.: 10/749,670

Examiner: Dennis ROSARIO

Filed: December 30, 2003

Art Unit: 2624

Confirmation No.: 9761

For: METHOD AND APPARATUS FOR DETECTING DEFECTS ON A
WAFER

Date: March 24, 2008

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT

Responsive to the Office Action, Paper No. 20071217, dated December 27, 2007, please amend the application as follows.

- **Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.
- **Remarks/Arguments** begin on page 7 of this paper.